

Reliability Prediction
 TR-NWT-332
 Issue 6

Device Reliability Prediction

Case 1 - Black Box Estimates (50% Stress, Temp. = 55 Deg. C,
 No Device burn-in)

Date: 9/6/2018	Page: 1 of 1
Unit: TPS84610RKGR-AS1	Manufacturer: Texas Instruments Inc., Warrenville, IL

<i>Device Type</i>	<i>Part Number</i>	<i>Circuit Ref Symbol</i>	<i>Qty</i>	<i>Failure Rate</i>	<i>Quality Factor</i>	<i>Total Device Failure Rate</i>
	072-00047		0.375		1	
	072-00005		0.014		1	
	071-00130		0.013		1	
Resistor, Comp < 1MOhm	052-23143	R1	1	0.6	1	0.6
Resistor, Comp < 1MOhm	051-25383	R3	1	0.6	1	0.6
Resistor, Comp < 1MOhm	051-24340	R5	1	0.6	1	0.6
Resistor, Comp < 1MOhm	051-23649	R2	1	0.6	1	0.6
Resistor, Comp < 1MOhm	051-14487	R4	1	0.6	1	0.6
Capacitor, Fixed, Ceramic	047-41033	C5	1	1.0	1	1.0
Capacitor, Fixed, Ceramic	047-41032	C1	1	1.0	1	1.0
Capacitor, Fixed, Ceramic	047-23300	C2,C4	2	1.0	1	2.0
	030-00269	L1	1		1	
IC, Analog	021-00111	U1	1	13.0	1	13.0

Total FIT Rate: 20.0

Equivalent MTBF (hrs): 50,000,000